

**ETS'09
Tutorials**

Monday, May, 25

9:00 – 13:00

**TTEP
Tutorial 1**
Advanced Topics and
Recent Advances in
Silicon Debug and Diagnosis

**TTEP
Tutorial 2**
Design for
Manufacturing

lunch

14:30 – 17:30

**TTEP
Tutorial 1**
Advanced Topics and
Recent Advances in
Silicon Debug and Diagnosis

**TTEP
Tutorial 2**
Design for
Manufacturing

20:00 – 22:00

Welcome Reception



**ETS'09
Program
At a
Glance**

Tuesday, May, 26

8:30 – 10:30

**Plenary Opening
Keynote Addresses**

10:30 – 11:30

Session 2 - POSTER I and Coffee Break

11:30 – 13:00

**Session 3A
Internal Testing of
Mixed-Signal Cores**

**Session 3B
Debug and
Validation**

**Session 3C
Vendor 1**

lunch

14:30 – 16:00

**Session 4A
Power Issues
During Test**

**Session 4B
Self-test and
Test Throughput**

**Session 4C
Vendor 2**

16:00 – 17:00

Session 5 - POSTER II and Coffee Break

17:00 – 18:00

**Session 6A
On-line Testing**

**Session 6B
Vendor 3**

18:00 – 19:30

**Session 7A
Panel 1
Yield, Reliability and
Variability in the Nano-Era**

**Session 7B
Panel 2
Extended Diagnosis Req.
in Automotive Applications**

**ETS'09
Program
At a
Glance**

Wednesday, May, 27

9:00 – 10:30

Session 8A
Advanced Testing
Mem., Power Trans.
Microfluidic Syst.

Session 8B
Recent Advances
in ATPG

Session 8C
Student's
Forum

10:30 – 11:30

**Session 9 - Coffee Break and
STUDENT'S POSTERS**

11:30 – 13:00

Session 10A
Advanced External
Test of Mixed-Signal
Cores

Session 10B
Diagnosis and
Dependability
Analysis

Session 10C
Special
Soft Errors in
Electronic Systems

lunch

14:30 – 15:30

Session 11A
Emb. Tutorial 1
Switching Noise and Process Var.
Challenges in Delay Testing

Session 11B
Emb. Tutorial 2
Test Challenges and Solutions
in TSV-Based 3D Stacked ICs

16:00 – 23:00

Social Program



**ETS'09
Program
At a
Glance**

Thursday, May, 28

9:00 – 10:30

Session 12A
Impact of Nanometer Technol.
in the Testing Methodology

Session 12B
DfT and
Embedded Test

10:30 – 11:30

Session 13 - POSTER III and Coffee Break

11:30 – 12:30

Session 14A
Emb. Tutorial 3
Ensuring High Testability
without Degrading Security

Session 14B
Emb. Tutorial 4
On-chip Delay Measurem. Tech.
for Production Test – from D to A

12:30 – 13:00

Session 15 - Plenary Closing

lunch



**ETS'09
Fringe
Workshop**

Friday, May, 29

9:00 – 13:00

Lp on TR

**Impact of Low-Power design
on Test and Reliability**

lunch

14:30 – 17:00

LP on TR

**Impact of Low-Power design
on Test and Reliability**